



# Reviewer's Recognition

The Editor-in-Chief and Editorial Board of the ASCE-ASME *Journal of Risk and Uncertainty in Engineering Systems, Part B: Mechanical Engineering* would like to thank all of the reviewers for volunteering their expertise and time reviewing manuscripts in 2021. Serving as reviewers for the journal is a critical service necessary to maintain the quality of our publication and to provide the authors with a valuable peer review of their work. Below is a complete list of reviewer's for 2021. We would also like to acknowledge two outstanding Reviewers of the Year.

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## 2021 Reviewers of the Year

**Chen Jiang** — Huazhong University of Science and Technology, China

**Imad Abdallah** — Eidgenössische Technische Hochschule Zürich, Switzerland

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The Reviewers of the Year Award is given to reviewers who have made an outstanding contribution to the journal in terms of the quantity, quality, and turnaround time of reviews completed during the past 12 months. The prize includes a Wall Plaque, 50 free downloads from the ASME Digital Collection, and a one year free subscription to the journal.

### List of RISK Reviewers

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M. Abaiee	H. Dixit	R. Maschotta
I. Abdallah	K. dos Santos	M. Michalski
S. Almeida	L. Driemeier	E. Monlevade
E. Antoniou	G. Duthé	C. Morais
A. Ariffin	H. Estrada Lugo	A. Morozov
L. Avendaño-Valencia	M. Faes	R. Moura
B. Ayyub	V. Fragkoulis	L. Moysis
J. Bae	S. Freitag	S. Nannapaneni
S. Barber	M. Futai	P. Nath
A. Beck	J. Gernand	I. Papaioannou
M. Beer	A. Glowacz	E. Patelli
M. Bittencourt	W. Gomes	C. Patiño Rogriguez
F. Campean	E. Gomi	F. Pereira
L. Celorrio	X. Han	T. Pires
A. Cicirello	C. Jiang	M. Pourgol-Mohammad
P. Cugnasca	B. Jou	M. Ramos
G. Cunha Barbosa	P. Karve	Y. Reuland
S. Dana	A. Kawano	S. Santosh
G. Datta	F. Khan	A. Schleder
P. David	G. Le Bris	E. Silva
M. De Angelis	H. Li	M. Soleimani
F. De Nolasco Santos	Y. Li	R. Stoeterau
C. de Oliveira Ribeiro	Y. Ma	K. Tatsis
G. de Souza	S. Marx	R. Tiwari
M. Diaconasa	Y. Marykovskiy	S. Tolo

A. Tran  
A. Veeramany  
B. Veitch

Z. Wang  
P. Wei  
J. Youbao

D. Zhang  
K. Zhang  
K. Zuev

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